

Amendments to the Specification

Paragraph [0026] has been amended as follows:

"Tester 14 has a simulation circuit 15, which provides one or more programs for the chip to execute, a control circuit 16, which controls the clock speeds, supply voltages, body-bias voltages, and programs of instruction sets used in the test, and the programs to be executed by the chip. The test can be performed on the entire chip and data can be entered into the table for the entire chip. Alternatively, the test can be perform on individual circuit blocks, or even on individual transistors or groups of transistors, and data can be entered into table 8 for each circuit block, transistor, or group of transistors. The test typically consists of determining whether the chip can successfully execute one or more programs at various clock speeds, supply voltages, body-bias voltages, and programs of instruction sets at various temperatures. Preferably, for use in battery-powered computers, the chip is tested at 2 to 4 different supply voltages between 1 and 4 volts, at 2 to 4 different body-bias voltages between -0.5 and +0.5 volts, and at 2 to 4 different clock speeds between 1 and 300 MHz at maximum and minimum desired temperatures. Preferably, for use in plug-in computers, the chip is tested at 2 to 4 different supply voltages between 1 and 4 volts, at 2 to 4 different body-bias voltages between -0.5 and +0.5 volts, and at 2 to 4 different clock speeds between 0.2 and 2 GHz at maximum and minimum desired temperatures. Of course, as chips improve, the preferred test voltages may fall while clock speeds increase. The test may also be performed at other conditions, such as at different temperatures, for example, between 0 and 110°C.

Typically, the data obtained is the minimum supply voltages and minimum body-bias voltages used in the test at which the chip successfully executed a program at each clock speed tested. The data may also show that the operating voltage values should be different from the predetermined voltage values, which may change the range of the operating voltages."